

SULIT



Final Examination
2018/2019 Academic Session

June 2019

**JIF418 – Semiconductor and Devices
(Semikonduktor dan Peranti)**

Duration : 3 hours
(Masa : 3 jam)

Please check that this examination paper consists of **SEVEN (7)** pages of printed material before you begin the examination.

*[Sila pastikan bahawa kertas peperiksaan ini mengandungi **TUJUH (7)** muka surat yang bercetak sebelum anda memulakan peperiksaan ini].*

Instructions : Answer **ALL** questions. You may answer **either** in Bahasa Malaysia or in English.

Arahan : Jawab **SEMUA** soalan. Anda dibenarkan menjawab soalan **sama ada** dalam Bahasa Malaysia atau Bahasa Inggeris].

In the event of any discrepancies, the English version shall be used.

[Sekiranya terdapat sebarang percanggahan pada soalan peperiksaan, versi Bahasa Inggeris hendaklah digunakan].

...2/-

SULIT

Answer **ALL** questions.

Jawab **KESEMUA** soalan.

1. With appropriate illustration/equation (if any), give your comments on the **truthfulness** of the following statements:

*Dengan menggunakan ilustrasi/persamaan yang bersesuaian (jika ada), berikan komen anda terhadap **kebenaran** pernyataan berikut:*

- (a). Ionised donor atoms create holes in the valence band.

Atom penderma yang terion membentuk lohong dalam jalur valens.

(5 marks/markah)

- (b). The Fermi level is constant in a $p-n$ junction during equilibrium.

Aras Fermi adalah malar dalam simpang $p-n$ semasa keseimbangan.

(5 marks/markah)

- (c). For charge carriers in a semiconductor at a specific temperature, their mobility can be known after measuring their diffusion coefficient.

Bagi pembawa cas dalam satu semikonduktor pada suhu tertentu, kelincahan mereka dapat diketahui selepas mengukur pekali resapan.

(5 marks/markah)

- (d). Majority carrier injection that occurs during reverse bias in a $p-n$ junction is dependant on the height of the potential barrier.

Suntikan pembawa majoriti yang berlaku semasa pincang songsang dalam satu simpang $p-n$ bersandar pada ketinggian sawar keupayaan.

(5 marks/markah)

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2. Polycrystalline silicon is loaded into a crucible with 5 mg Boron to achieve 10^{15} cm^{-3} doping in a Czochralski growth.

Polihablur silikon dimasukkan ke dalam satu mangkuk pijar bersama dengan 5 mg Boron bagi mendapatkan pendopan 10^{15} cm^{-3} dalam satu pertumbuhan Czochralski.

- (a). Calculate the mass of the polycrystalline Si.

Hitung jisim polihabur Si tersebut.

(10 marks/markah)

- (b). With the help of diagrams and equations, elaborate on how to produce the polycrystalline Si.

Dengan bantuan gambar rajah dan persamaan, huraikan cara bagi menghasilkan polihablur Si tersebut.

(10 marks/markah)

3. A Si sample at 300 K is doped with 10^{16} phosphorus cm^{-3} .

Satu sampel Si pada 300 K didopkan dengan 10^{16} fosforus cm^{-3} .

- (a). Calculate the difference in the energy between the Fermi level and conduction band edge.

Hitung perbezaan tenaga di antara aras Fermi dan pinggir jalur konduksi.

(10 marks/markah)

- (b). The sample is then steadily illuminated. If the steady state optical generation rate is $2 \times 10^{22} \text{ EHP cm}^{-3} \text{ s}^{-1}$ and the recombination coefficient is $10^{-7} \text{ cm}^3 \text{ s}^{-1}$, calculate the steady state excess carrier concentration.

Sampel tersebut kemudiannya disinari secara mantap. Jika kadar penjanaan optikal keadaan mantap ialah $2 \times 10^{22} \text{ EHP cm}^{-3} \text{ s}^{-1}$ dan pekali rekombinasi ialah $10^{-7} \text{ cm}^3 \text{ s}^{-1}$, hitung kepekatan pembawa lebihan keadaan mantap.

(10 marks/markah)

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4. (a). A light having an energy of 2.5 eV and a power of 8 mW illuminates a 0.3 μm thick semiconductor. If the absorption coefficient at the wavelength of light is $5.1 \times 10^4 \text{ cm}^{-1}$, how many photons per second will be emitted during the luminescence?

Satu cahaya dengan tenaga 2.5 eV dan kuasa 8 mW menyinari satu semikonduktor yang ketebalannya 0.3 μm . Jika pekali penyerapan pada panjang gelombang tersebut ialah $5.1 \times 10^4 \text{ cm}^{-1}$, berapakah foton per saat akan dilecitkan semasa luminesens?

(10 marks/markah)

- (b). The electron concentration in a semiconductor is given by
Kepekatan elektron dalam satu semikonduktor diberikan oleh

$$n(x) = 10^{16} \left(1 - \frac{x}{L} \right) \text{ cm}^{-3}$$

between $0 \leq x \leq L$, where $L = 10 \mu\text{m}$. The semiconductor has a constant total current density of -85 A cm^{-2} over the given x range. If the electron diffusion coefficient is $26 \text{ cm}^2 \text{ s}^{-1}$ and electron mobility is $1000 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$, determine the electric field at $x = 2 \mu\text{m}$.

di antara $0 \leq x \leq L$, dengan $L=10 \mu\text{m}$. Semikonduktor tersebut mempunyai jumlah ketumpatan arus malar -85 A cm^{-2} merentasi julat x tersebut. Jika pekali resapan elektron ialah $26 \text{ cm}^2 \text{ s}^{-1}$ dan kelincahan elektron ialah $1000 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$, tentukan medan elektrik di $x = 2 \mu\text{m}$.

(10 marks/markah)

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5. An abrupt Si p - n junction is doped with 10^{17} cm^{-3} acceptor atoms on the p side and 10^{16} cm^{-3} donor atoms on the n side.

Satu simpang langkah p - n didop dengan atom penderma 10^{17} cm^{-3} di bahagian p dan atom penderma 10^{16} cm^{-3} di bahagian n .

- (a). At 300 K,

Pada suhu 300 K,

- (i). calculate the contact potential.

hitung keupayaan sentuh.

(5 marks/markah)

- (ii). sketch an equilibrium band diagram for the junction. Label the contact potential.

lakar satu gambar rajah jalur keseimbangan bagi simpang tersebut. Label keupayaan sentuh.

(5 marks/markah)

- (b). With the help of diagrams, elaborate on the formation of the forward current in the junction.

Dengan bantuan gambar rajah, huraikan pembentukan arus depan dalam simpang tersebut.

(10 marks/markah)

Useful Information:

Avogadro's number, $N_A = 6.02 \times 10^{23}$ molecules/mole

Nombor Avogadro, $N_A = 6.02 \times 10^{23}$ molekul/mol

Boltzmann's constant, $k = 1.38 \times 10^{-23} \text{ J K}^{-1} = 8.62 \times 10^{-5} \text{ eV K}^{-1}$

Pemalar Boltzman, $k = 1.38 \times 10^{-23} \text{ J K}^{-1} = 8.62 \times 10^{-5} \text{ eV K}^{-1}$

Charge of electron, $e = 1.6 \times 10^{-19} \text{ C}$

Cas elektron, $e = 1.6 \times 10^{-19} \text{ C}$

Mass of electron, $m = 9.11 \times 10^{-31} \text{ kg}$

Jisim elektron, $m = 9.11 \times 10^{-31} \text{ kg}$

Planck's constant, $h = 6.63 \times 10^{-34} \text{ J s} = 4.14 \times 10^{-15} \text{ eV s}$

Pemalar Planck, $h = 6.63 \times 10^{-34} \text{ J s} = 4.14 \times 10^{-15} \text{ eV s}$

Permittivity of free space, $\epsilon_0 = 8.85 \times 10^{-12} \text{ C}^2 \text{ N}^{-1} \text{ m}^2$

Ketelusan ruang bebas, $\epsilon_0 = 8.85 \times 10^{-12} \text{ C}^2 \text{ N}^{-1} \text{ m}^2$

Relative dielectric constant of Si, $\epsilon_r = 11.8$

Pemalar dielektrik relatif Si, $\epsilon_r = 11.8$

Speed of light, $c = 3 \times 10^8 \text{ m s}^{-1}$

Laju cahaya, $c = 3 \times 10^8 \text{ m s}^{-1}$

Ingot	Dopant <i>Pendop</i>	Segregation coefficient of dopant, k_d <i>Pekali pemisahan dopan, k_d</i>	Atomic weight (g mol ⁻¹) <i>Berat atom (g mol⁻¹)</i>
Si $\rho = 2.33 \text{ g cm}^{-3}$	B	0.8	10.8
	Al	0.0028	26.9
	P	0.35	30.9
	As	0.3	74.9
GaAs $\rho = 5.31 \text{ g cm}^{-3}$	Zn	0.42	65.4
	Si	2	28.1
	Se	0.1	78.9
	Te	0.064	127.6

Constants at 300 K <i>Pemalar pada 300 K</i>	Ge	Si	GaAs
Energy bandgap, E_g <i>Jurang jalur tenaga, E_g</i>	0.66 eV	1.12 eV	1.42 eV
Intrinsic carrier concentration, n_i <i>Kepekatan pembawa intrinsik, n_i</i>	$2.4 \times 10^{13} \text{ cm}^{-3}$	$1.5 \times 10^{10} \text{ cm}^{-3}$	$1.8 \times 10^6 \text{ cm}^{-3}$
Conduction band effective density of states, N_c <i>Ketumpatan berkesan jalur konduksi, N_c</i>	$1.04 \times 10^{19} \text{ cm}^{-3}$	$2.8 \times 10^{19} \text{ cm}^{-3}$	$4.7 \times 10^{17} \text{ cm}^{-3}$
Valence band effective density of states, N_v <i>Ketumpatan berkesan jalur valens, N_v</i>	$6 \times 10^{18} \text{ cm}^{-3}$	$1.04 \times 10^{19} \text{ cm}^{-3}$	$7 \times 10^{18} \text{ cm}^{-3}$